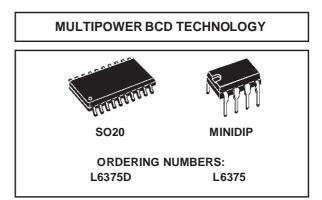


# L6375

PRELIMINARY DATA

## 0.5A INDUSTRIAL INTELLIGENT POWER SWITCH

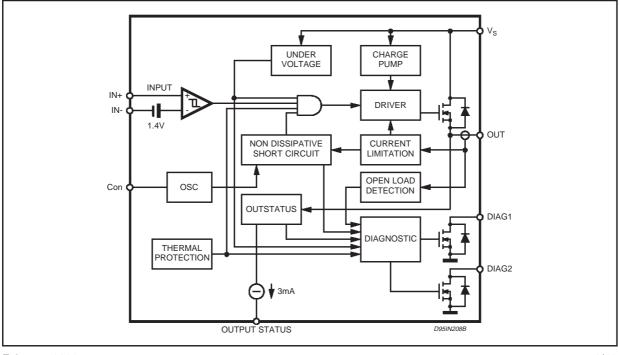
- 0.5A OUTPUT CURRENT
- 8V TO 35V SUPPLY VOLTAGE RANGE
- NON DISSIPATIVE SHORT CIRCUIT PROTECTION
- THERMAL SHUTDOWN
- OPEN GROUND PROTECTION
- NEGATIVE VOLTAGE CLAMPING FOR FAST DEMAGNETIZATION
- UNDERVOLTAGE LOCKOUT WITH HYSTERESIS
- OPEN LOAD DETECTION
- TWO DIAGNOSTIC OUTPUTS
- OUTPUT STATUS LED DRIVER
- IMMUNITY AGAINST BURST TRANSIENT (IEC 801-4), see application schematic.
- ESD PROTECTION (HUMAN BODY MODEL ±2KV)



#### DESCRIPTION

The L6375 is a monolithic fully protected, full diagnostic 0.5A Intelligent Power Switch. it is designed to drive any kind of R-L-C load with controlled output voltage slew rate and non dissipative short circuit protection. An internal Clamping Diode enables the fast demagnetization of inductive loads. Diagnostic for CPU feedback and extensive use of electrical protections make this device extremely rugged and specially suitable for industrial automation applications.

#### **BLOCK DIAGRAM**



#### February 2000

This is preliminary information on a new product now in development or undergoing evaluation. Details are subject to change without notice.

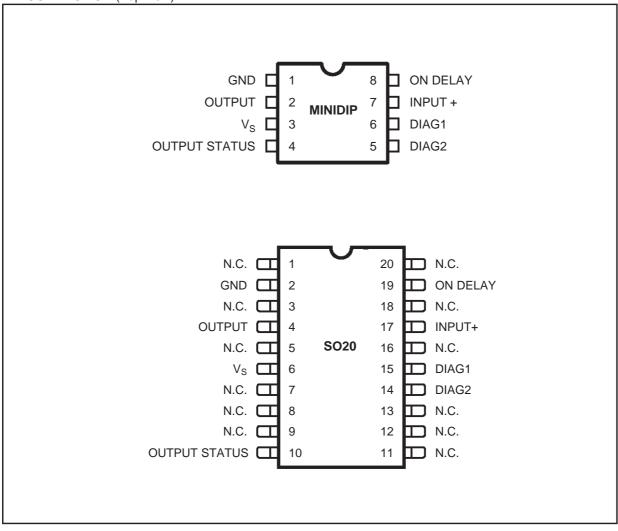
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#### L6375

N°	Pin	Description
1	GND	Ground
2	OUT	High side output. Controlled output with current limitation
3	Vs	Supply voltage input. Range with under voltage monitoring
4	OUTPUT STATUS	Led driver to signal the status of the output pin. The pin is active (sources current) when the output is considered high. (See fig. 1)
5	DIAG1	Diagnostic 1 output. This open drain reports the IC working conditions. (See Diagnostic truth table)
6	DIAG2	Diagnostic 2 output. This open drain reports the IC working conditions. (See Diagnostic truth table)
7	IN+	Comparator non inverting input
8	ON DELAY	Delay setting for overcurrent diagnostic

#### **PIN FUNCTION** (Pin numbering referred to Minidip package)

#### PIN CONNECTION (Top view)



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Symbol	Pin	Parameter	Value	Unit
Vs	3	Supply Voltage (tw < 10 ms)	50	V
Vs	3	Supply Voltage (DC)	40	V
Vs -Vout	3 vs 2	Supply to Output Differential voltage	internally limited	
Vod	5	Externally Forced Voltage	-0.3 to 7	V
lod	5	Externally Forced Current	±1	mA
lout	2	Output Current (see also Isc)	internally limited	
Vout	2	Output Voltage	internally limited	V
Ptot		Power Dissipation	internally limited	
Vdiag	5.6	External voltage	-0.3 to 40	V
Idiag	5.6	Externally forced current	-10 to 10	mA
li	7	Input Current	20	mA
Vi	7	Input Voltage	-10 to Vs +0.3	V
T <sub>op</sub>		Ambient temperature, operating range	-25 to 85	°C
Tj		Junction temperature, operating range (see Overtemperature Protection)	-25 to 125	°C
Tstg		Storage temperature	-55 to 150	°C
EI		Energy Induct. Load T <sub>J</sub> = 85°C	200	mJ

<b>ABSOLUTE MAXIMUM RATINGS</b>	(Pin	numbering	referred	to Minidip	package)
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#### THERMAL DATA

Symbol	Parameter	Minidip	SO20	Unit
R <sub>th j-case</sub>	Thermal Resistance Junction to Case Max.			°C/W
R <sub>th j-amb</sub>	Thermal Resistance Junction to Ambient Max.	100	90	°C/W

#### **ELECTRICAL CHARACTERISTCS**

(V<sub>S</sub> = 24V;  $T_j$  = -25 to +125°C, unless otherwise specified; pin numbering referred to Minidip package)

Symbol	Pin	Parameter	Test Condition	Min.	Тур.	Max.	Unit
Vsmin	3	Supply Voltage for Valid Diagnostic	Idiag = >0.5mA;Vdiag = 1.5V;	4		35	V
Vs	3	Operative Supply Voltage		8	24	35	V
Vsth1	3	Undervoltage Threshold 1	(See fig. 2)	7	7.5	8	V
Vsth2	3	Undervoltage Threshold 2	(See fig. 2)	6.5	7	7.5	V
Vshys	3	Under Voltage Hysteresis		300	500	700	mV
lq	3	Quiescent Current	Output Open		800		μΑ
Iqo	3	Quiescent Current	Output On		1.6		mA
Vith	7	Input Threshold Voltage		0.8	1.3	2	V
Viths	7	Input Threshold Hysteresis		50		400	mV
Vil	7	Input Low Level Voltage		-7		0.8	V
Vih	7	Input High Level Voltage	V <sub>s</sub> < 18V	2		V <sub>s</sub> -3	V
Vih	7	Input High Level Voltage	V <sub>s</sub> > 18V	2		15	V
lib	7	Input Bias Current	V <sub>i</sub> = -7 to 15V	-250		250	μΑ
Idch	5	Delay Capacitor Charging Current	ON DELAY pin shorted to Ground		2.5		μΑ
Vdon		Output Voltage Drop	$      I_{out} = 500 \text{mA } T_j = 25^{\circ}\text{C} \\       T_j = 125^{\circ}\text{C} \\       I_{out} = 625 \text{mA } T_j = 25^{\circ}\text{C} \\       T_j = 125^{\circ}\text{C} $		200 320 250 400	280 440 350 550	mV mV mV mV
lolk	2	Output Leakage Current	V <sub>i</sub> = LOW; V <sub>out</sub> =0			100	μΑ
Vol	2	Output Low State Voltage	Vi = HIGH; pin floating		0.8	1.5	V
Vcl	2	Internal Voltage Clamp (V <sub>s</sub> -V <sub>out</sub> )	lo = 200mA single pulsed =300µs	48	53	58	V
lsc	2	Short Circuit Output Current	$V_s = 8$ to 35V; $R_l = 2\Omega$ ;	0.75	1.1	1.5	Α
old	2	Open Load Detection Current	$V_i = V_{ih}$ ; $T_{amb} = 0$ to +85°C	1	3	6	mA
Voth1	5.6	Output Status Threshold 1 Voltage	(See fig. 1)	4.5	5	5.5	V
Voth2	5.6	Output Status Threshold 2 Voltage	(See fig. 1)	4	4.5	5	V
Vohys	5.6	Output Status Threshold Hysteresis	(See fig. 1)	300	500	700	mV
losd	5.6	Output Status Source Current	Vout > Voth1 ; Vos = 2.5V	2		4	mA

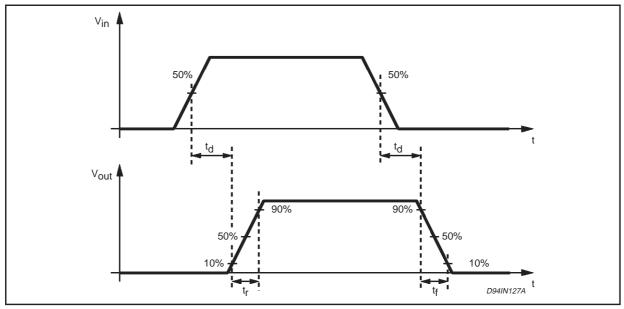
Symbol	Pin	Parameter	Test Condition	Min.	Тур.	Max.	Unit
Vosd	5.6	Active Output Status Driver Drop Voltage	$V_s - V_{os}$ ; los = 2mA Tamb = 0 to +85°C		1.5	3	V
losik	5.6	Output Status Driver Leakage Current	Vout < Voth2 ; Vos = 0V V <sub>S</sub> = 18 to $35V$			25	μΑ
Vdgl	5.6	Diagnostic Drop Voltage	D1 / D2 = L ; $I_{diag}$ = 0.5mA D1 / D2 = L ; $I_{diag}$ = 3mA		40 250		mV mV
ldglk	5.6	Diagnostic Leakage Current	D1 / D2 = H ; 0 < V <sub>dg</sub> < V <sub>s</sub> V <sub>S</sub> = 15.6 to 35V			5	μΑ
Tmax		Over Temperature Upper Threshold			150		°C
Thys		Over Temperature Hysteresis			20		°C
AC OPER	RATIO	N (pin numbering referred to M	inidip package)	1		1	
tr -tf	2	Rise or Fall Time	$Vs = 24V; R_1 = 70\Omega R_1$ to ground		20		μs
td	2	Delay Time	$Vs = 24V; RI = 70\Omega R_1$ to ground		5		μs
dV/dt	2	Slew Rate (Rise and Fall Edge)	50pF < C <sub>DON</sub> < 2nF	7	1	15	V/µs
t <sub>ON</sub>	8	On time during Short Circuit Condition			128		μs/pF
tOFF	8	Off time during Short Circuit Condition			64		μs/pF
f <sub>max</sub>		Maximum Operating Frequency			25		KHz
SOURCE	DRA	IN NDMOS DIODE	,				
V <sub>f</sub>		Forward On Voltage	@ lfsd = 625mA		1	1.5	V
I <sub>fD</sub>		Forward Peak Voltage	t = 10ms; d = 20%			2	A
t <sub>rr</sub>		Reverse Recovery Time	l <sub>f</sub> = 625mA di/dt = 25A/μs		200		ns
t <sub>fr</sub>		Forward Recovery Time			50		ns

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### ELECTRICAL CHARACTERISTCS (Continued)



#### Figure 1. Switching Waveforms



#### INPUT SECTION

An Single ended Input TTL/CMOS compatible with wide voltage range and high noise immunity (thanks to a built in hysteresis) is available.

#### **OVER TEMPERATURE PROTECTION (OVT)**

An on-chip Over Temperature Protection provides an excellent protection of the device in extreme conditions. Whenever the temperature - measured on a central portion of the chip- exceeds Tmax=150 C (typical value) the device is shut off, and the DIAG2 output goes LOW. Normal operation is resumed as the chip temperature (normally after few seconds) falls below Tmax-Thys= 130 C (typical value). The hysteresis avoid thats an intermittent behaviour take place.

#### **UNDER VOLTAGE PROTECTION (UV)**

The supply voltage is expected to range from 8 to 35 V. In this range the device operates correctly. To avoid any misfunctioning the supply voltage is continuously monitored to provide an under voltage protection. As Vs falls below Vsth-Vshys (typically 7.5 V, see fig.1) the output power MOS is switched off and DIAG1 and DIAG2 (see Diagnostic truth table). Normal operation is resumed as soon as Vs exceeds Vsth. The hysteretic behaviour prevents intermittent operation at low supply voltage.

#### OVER CURRENT OPERATION

In order to implement a short circuit protection the output power MOS is driven in linear mode to limit the output current to the Isc (1.1A typical value). This condition (current limited to the Isc value) lasts for a Ton time interval, that can be set by means of a capacitor (Cdon) connected to the ON DELAY pin according to the following formula:

Ton = 1.28 msec/pF

for

50pF<Cdon< 2nF

After the Ton interval has expired the output power MOS is switched off for the Toff time interval with:

Toff =  $64 \cdot Ton$ .

When also the Toff interval has expired, the out-put power MOS is switched ON. At this point in time two con-

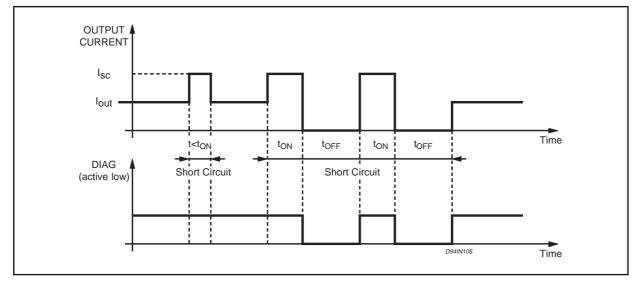


ditions may occur

- A) the overload is still present, and then the output power MOS is again driven in linear mode (limiting the output current to lsc) for another Ton, starting a new cycle, or
- B) the overload condition is removed, and the output power MOS is no longer driven in linear mode. All these occurrences are presented on the DIAG2 pin (see fig 2).

We call this unique feature **Non Dissipative Short Circuit Protection** and it ensures a very safe operation even in permanent overload conditions. Note that choosing the most appropriate value for the Ton interval (i.e. the value of the Cdon capacitor) a delay (the Ton itself) will prevent that a misleading Short Circuit information is presented on the DIAG2 output, when driving capacitive loads (that acts like short circuit in the very beginning) or Incandescent Lamp (a cold filament has a very low resistive value). The Non Dissipative Short Circuit Protection can be disabled (keeping Ton = 0 but with the output current still limited to Isc, and Diagnostic disabled)simply shorting to ground the the ON DELAY pin.





#### **DIAGNOSTIC LOGIC**

The operating conditions of the device are permanently monitored and the following occurrences are signalled via the DIAG1/DIAG2 open-drain output pins see: diagnostic Truth Table.

- Short Circuit versus ground.
- Short Circuit versus  $\mathsf{V}_{S}$
- Under Voltage(UV)
- Over Temperature (OVT)
- Open Load, if the output current is less than 3mA (typical value).

#### DEMAGNETIZATION OF INDUCTIVE LOADS

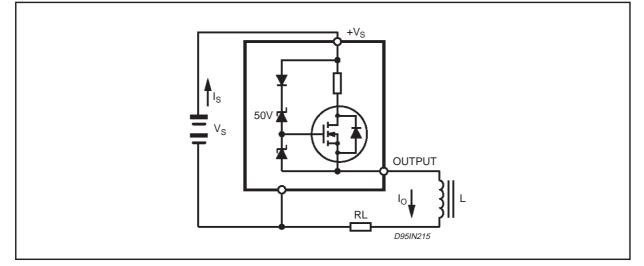
An internal zener diode, limiting the voltage across the Power MOS to between 50 and 60V (V<sub>cl</sub>), provides safe and fast demagnetization of inductive loads without external clamping devices. The maximum energy that can be absorbed from an inductive load is specified as 200mJ (at  $T_i = 85^{\circ}C$ )



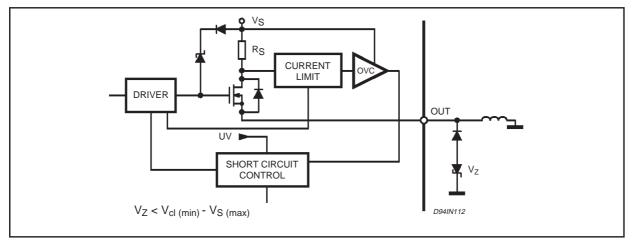
#### DIAGNOSTIC TRUTH TABLE

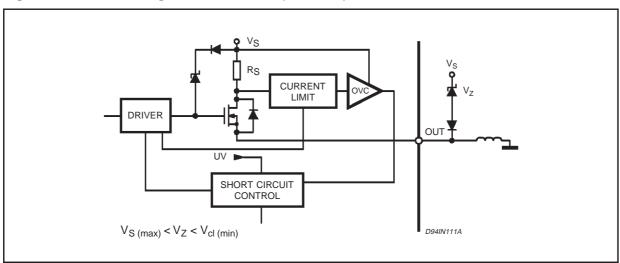
Diagnostic Conditions	Input	Output	DIAG1	DIAG2
Normal Operation	L H	L H	H H	H H
Open Load Condition (I <sub>o</sub> < I <sub>old</sub> )	L H	L H	H L	H H
Short to V <sub>S</sub>	L H	H H	L	H H
Short Circuit to Ground (I <sub>O</sub> = I <sub>SC</sub> ) (pin ON-DELAY grounded)	Н	H L	H H	H H
Output DMOS Open	L H	L	H L	H H
Overtemperature	L H	L	H H	L L
Sumplay Undervoltage (V <sub>S</sub> < V <sub>sth2</sub> )	L H	L	L	L

#### Figure 3. Inductive Load Equivalent Circuit



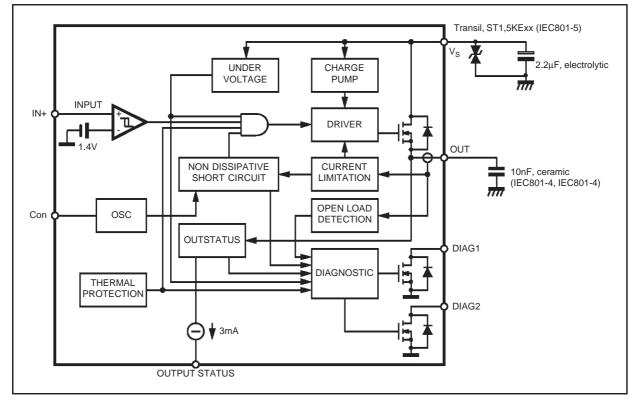
#### Figure 4. External Demagnetisation Circuit (versus ground)



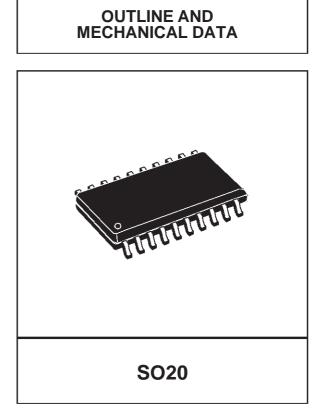


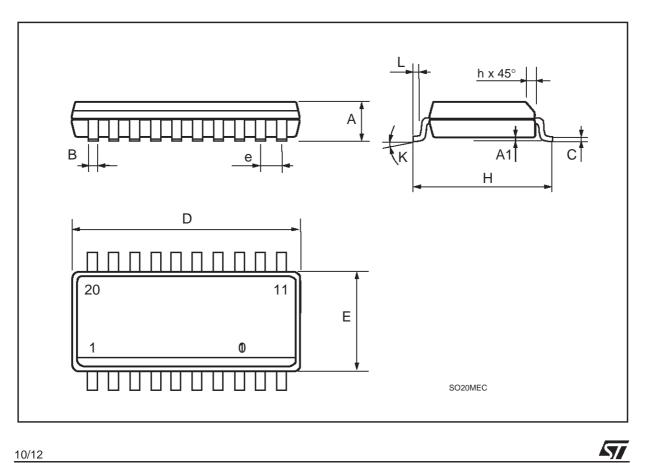
#### Figure 5. External Demagnetisation Circuit (versus \s)





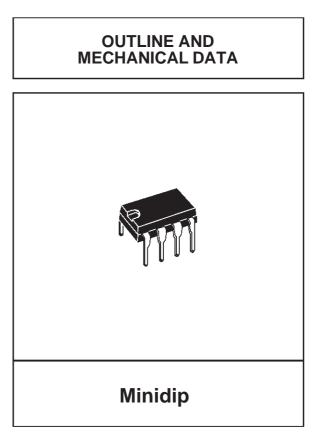
DIM.		mm			inch	
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	2.35		2.65	0.093		0.104
A1	0.1		0.3	0.004		0.012
В	0.33		0.51	0.013		0.020
С	0.23		0.32	0.009		0.013
D	12.6		13	0.496		0.512
E	7.4		7.6	0.291		0.299
е		1.27			0.050	
н	10		10.65	0.394		0.419
h	0.25		0.75	0.010		0.030
L	0.4		1.27	0.016		0.050
к		(	D° (min.)	8° (max.)	)	

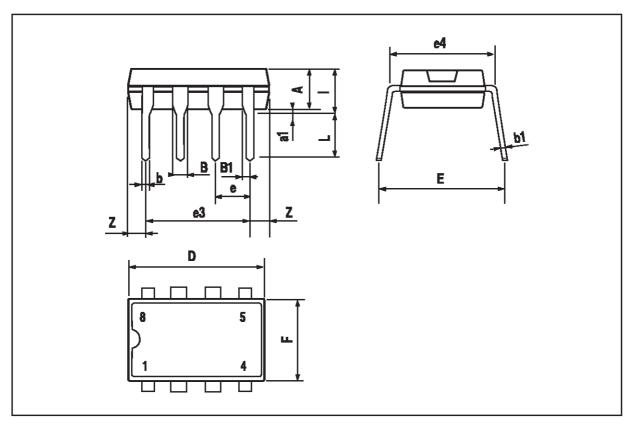




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DIM.		mm			inch	
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А		3.32			0.131	
a1	0.51			0.020		
В	1.15		1.65	0.045		0.065
b	0.356		0.55	0.014		0.022
b1	0.204		0.304	0.008		0.012
D			10.92			0.430
E	7.95		9.75	0.313		0.384
е		2.54			0.100	
e3		7.62			0.300	
e4		7.62			0.300	
F			6.6			0.260
I			5.08			0.200
L	3.18		3.81	0.125		0.150
Z			1.52			0.060





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